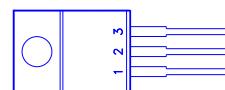
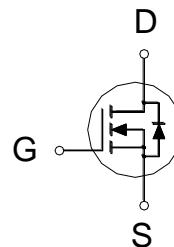


NIKO-SEM**N-Channel Enhancement Mode
Field Effect Transistor****P0610BT
TO-220
Halogen-Free & Lead-Free****PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D^2
100V	6.5mΩ	120A

**ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS		UNITS
Drain-Source Voltage		V_{DS}	100		V
Gate-Source Voltage		V_{GS}	± 20		V
Continuous Drain Current ²	$T_C = 25^\circ\text{C}$	I_D	120		A
	$T_C = 100^\circ\text{C}$		76		
Pulsed Drain Current ¹		I_{DM}	375		
Avalanche Current		I_{AS}	39		
Avalanche Energy	$L = 1\text{mH}$	E_{AS}	770		mJ
Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	208		W
	$T_C = 100^\circ\text{C}$		83		
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150		°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		0.6	
Junction-to-Ambient	$R_{\theta JA}$		62.5	°C / W

¹Pulse width limited by maximum junction temperature.²Package limitation current is 110A**ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	100			
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.3	1.8	2.3	V
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 80\text{V}, V_{GS} = 0\text{V}$			1	
		$V_{DS} = 80\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$			10	μA

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Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 4.5V, I_D = 20A$	5.8	8	$m\Omega$
		$V_{GS} = 10V, I_D = 20A$	5.3	6.5	
Forward Transconductance ¹	g_{fs}	$V_{DS} = 10V, I_D = 20A$	140		S
DYNAMIC					
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$	6188		pF
Output Capacitance	C_{oss}		747		
Reverse Transfer Capacitance	C_{rss}		233		
Gate Resistance	R_g		1.26		Ω
Total Gate Charge ²	$Q_{g(VGS=10V)}$	$V_{DS} = 50V, I_D = 20A$	121		nC
	$Q_{g(VGS=4.5V)}$		64.2		
Gate-Source Charge ²	Q_{gs}		15.8		
Gate-Drain Charge ²	Q_{gd}		30		
Turn-On Delay Time ²	$t_{d(on)}$	$V_{DD} = 50V,$ $I_D \approx 20A, V_{GS} = 10V, R_{GEN} = 6\Omega$	20		nS
Rise Time ²	t_r		60		
Turn-Off Delay Time ²	$t_{d(off)}$		55		
Fall Time ²	t_f		57		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)					
Continuous Current ³	I_S			120	A
Forward Voltage ¹	V_{SD}	$I_F = 20A, V_{GS} = 0V$		1.2	V
Reverse Recovery Time	t_{rr}	$I_F = 20A, dI/dt = 100A/\mu s$	58		nS
Reverse Recovery Charge	Q_{rr}		136		nC

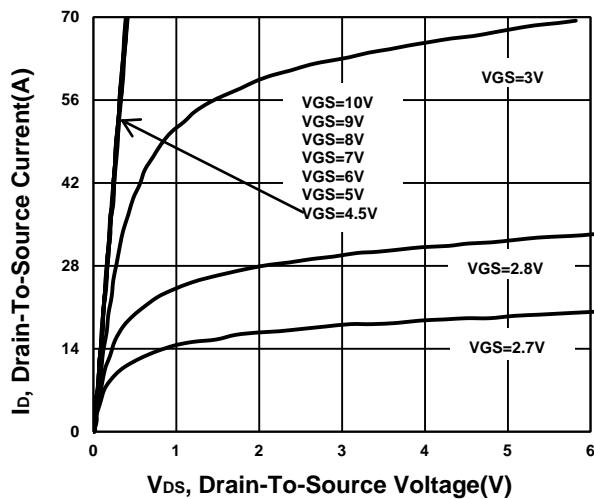
¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.³Package limitation current is 110A

NIKO-SEM

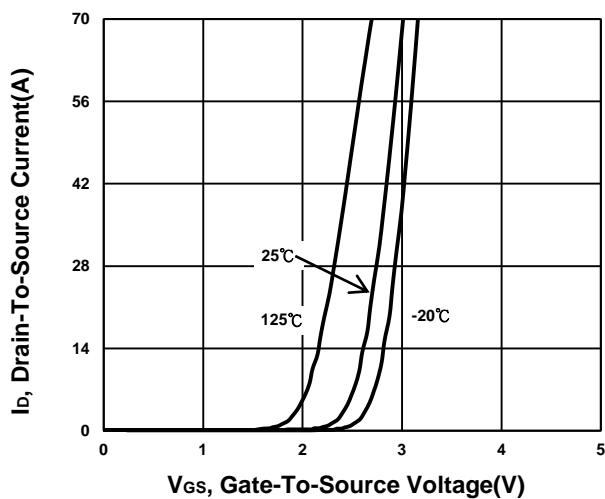
**N-Channel Enhancement Mode
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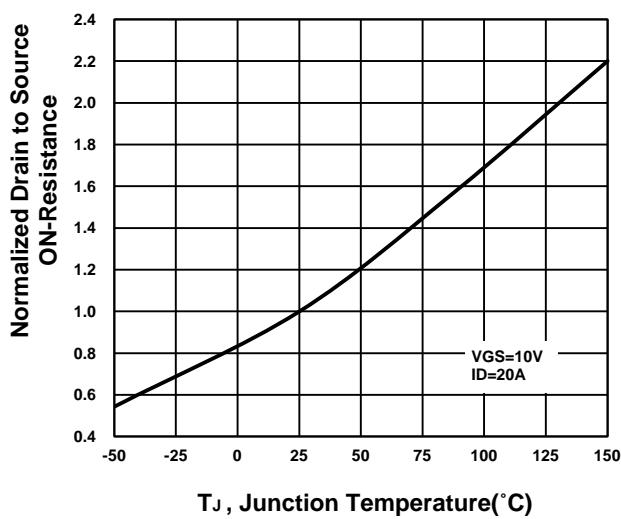
Output Characteristics



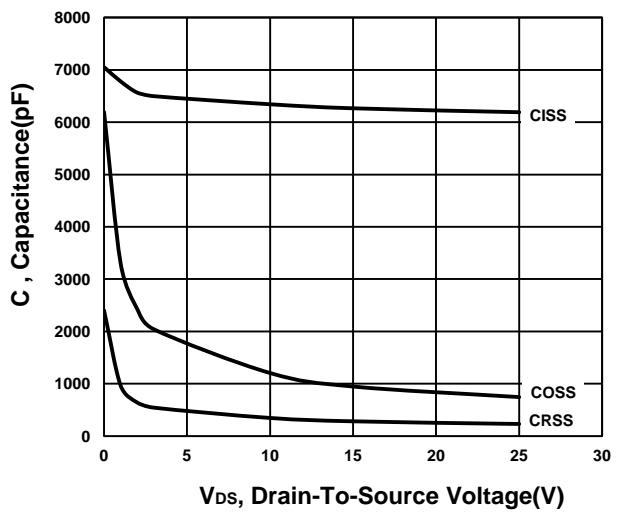
Transfer Characteristics



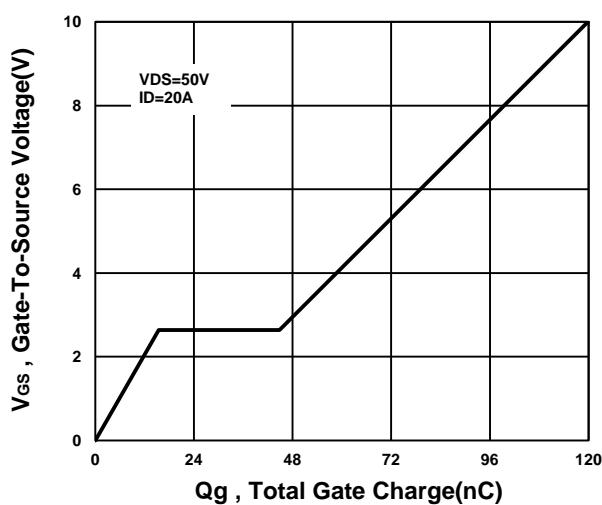
On-Resistance VS Temperature



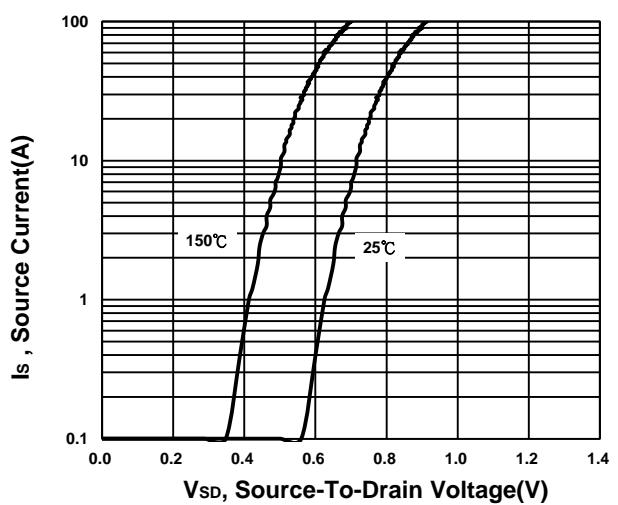
Capacitance Characteristic



Gate charge Characteristics



Source-Drain Diode Forward Voltage

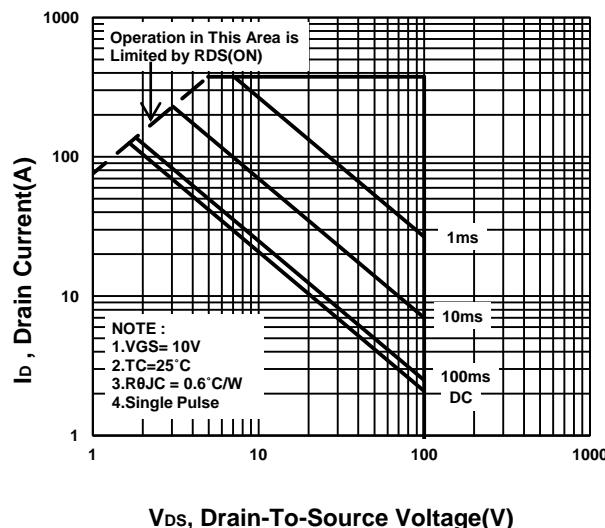


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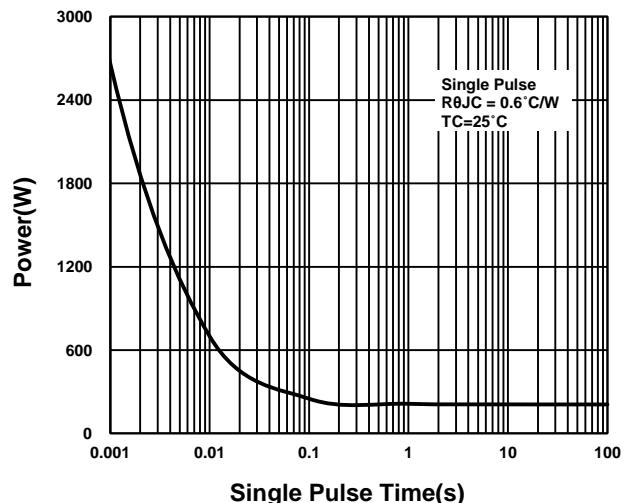
**N-Channel Enhancement Mode
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Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve

